MANUFACTURING MADE LIGHT

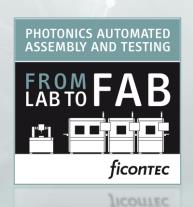
ficontec photonics assembly & testing

Solutions for integrated photonics. Built to scale.

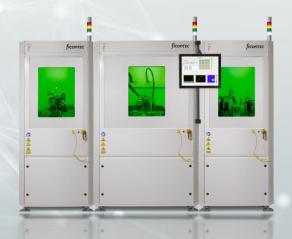




Technology developments & equipment concepts for scaling up photonics production for datacentres

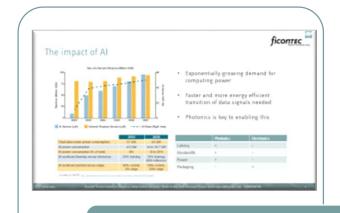


Malte Ennen, Sales Manager Europe



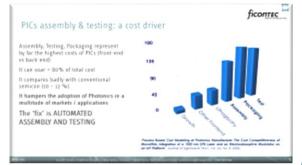


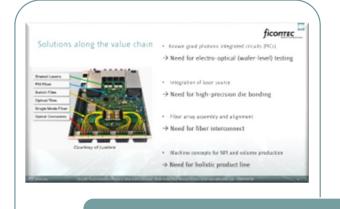
Outline



The impact of Al



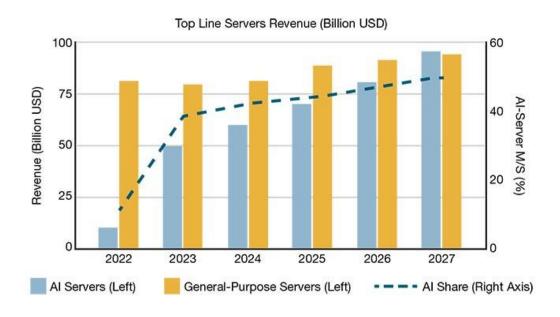




Our solutions



The impact of Al



	2023	2028
Total data center power consumption	57 GW	93 GW
Al power consumption	4.5 GW	14 to 18.7 GW
Al power consumption (% of total)	8%	15 to 20%
Al workload (training versus inference)	20% training	15% training, 85% inference
Al workload (central versus edge)	95% central, 5% edge	50% central, 50% edge

Courtesy of SOITEC https://www.photonics.com/Articles/Has_Silicon_Photonics_Finally_Found_Its_Killer/p5/vo252/i1782/a69704

- Exponentially growing demand for computing power
- Faster and more energy efficient transition of data signals needed
- Photonics is key to enabling this new revolution of communication

	Photonics	Electronics
Latency	Ŧ	-
Bandwidth	+	-
Power	+	-
Packaging	-	+



Transition of data center architecture

2019 ~2028

12.8 Tbps



Evolution toward CPO assembly with pluggable ELS modules on the switch PCBA



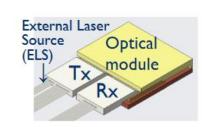


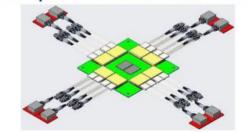
32x 400G QSFP-DD or OSFP



QSFP-DD W: 18.35 mm, L: 89.4 mm and T: 8.5 mm **OSFP** W: 22.58 mm, L: 107.8 mm and T: 13.0 mm

Evolution toward CPO optical modules





8x optical modules for CPO

CPO optical module W: ~20 mm, L: ~60 mm

Courtesy of Yole

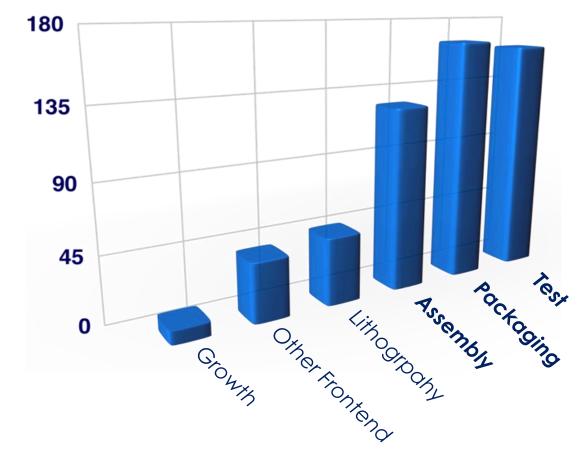
18.04.2024



PICs assembly & testing: a cost driver

- Assembly, Testing, Packaging represent by far the highest costs
- It can soar > 80% of total cost
- It compares badly with conventional semicon (10 - 12 %)
- It hampers the adoption of Photonics in a multitude of markets

The 'fix' is AUTOMATED ASSEMBLY AND TESTING



'Process-Based Cost Modeling of Photonics Manufacture: The Cost Competitiveness of Monolithic Integration of a 1550-nm DFB Laser and an Electroabsorptive Modulator on an InP Platform', Journal of Lightwave Tech, Vol. 24, No. 8, 2006.

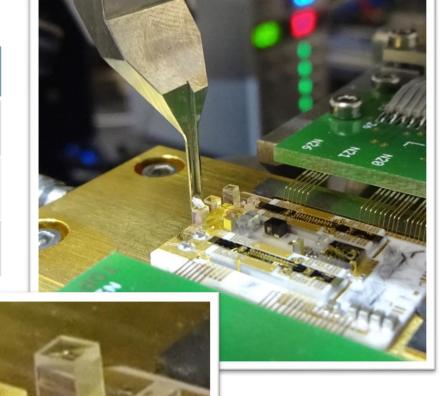


Flexibility vs speed: a matter of volumes

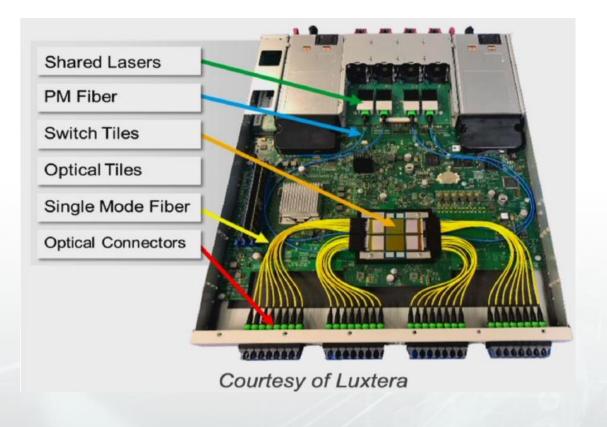
Numbers	Placement & Alignment	Machine Vision	Testing	Speed
Few tens	Manual	Only visual aids	Off-line / absent	Tens of minutes to hours
Few hundreds to few thousands	Automated / semi-automated	Automated feature detections and guidance	In line	Few minutes
Tens to hundreds of thousands (millions?)	Fully automated	Automated feature detections and guidance	In line	Tens of seconds



 Development of process and approach on a complex system in order to derive the high-volume approach





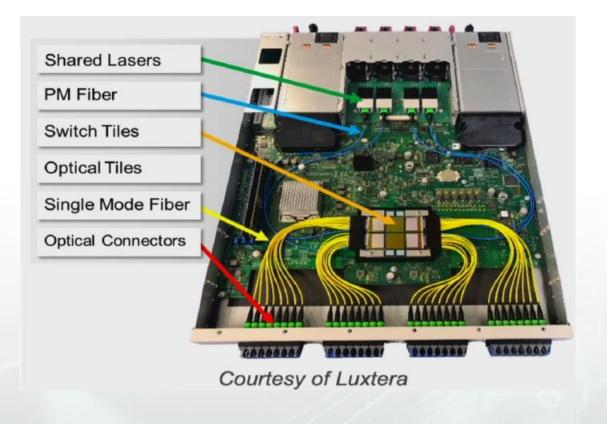


- Known good photonic integrated circuits (PICs)
- → Need for electro-optical (wafer-level) testing

- Integration of laser source
- → Need for high-precision die bonding
- Fiber array assembly and alignment
- → Need for fiber interconnect

- Machine concepts for NPI and volume production
- → Need for holistic product line





- Known good photonic integrated circuits (PICs)
- → Need for electro-optical (wafer-level) testing

- Integration of laser source
- → Need for high-precision die bonding
- Fiber array assembly and alignment
- → Need for fiber interconnect

Machine concepts for NPI and volume production



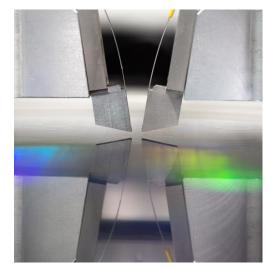
Electro-optical wafer-level testing



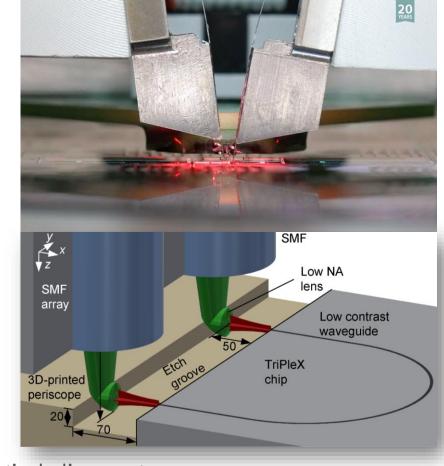
Electro-optical wafer-level tester for verification of PIC functionality

18.04.2024



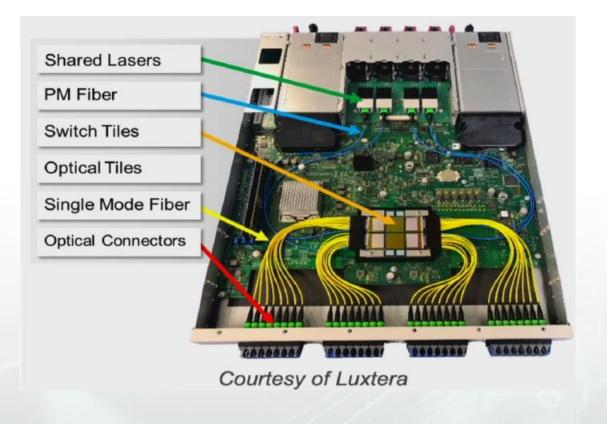


Wafer table



Optical alignment





- Known good photonic integrated circuits (PICs)
- → Need for electro-optical (wafer level) testing

- Integration of laser source
- → Need for high-precision die bonding
- Fiber array assembly and alignment
- → Need for fiber interconnect

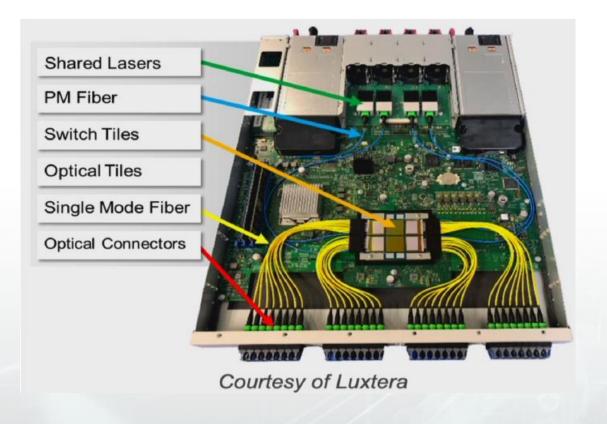
Machine concepts for NPI and volume production



ASSEMBLYLINE

Through-silicon Align-&-attach with IR





- Known good photonic integrated circuits (PICs)
- → Need for electro-optical (wafer level) testing

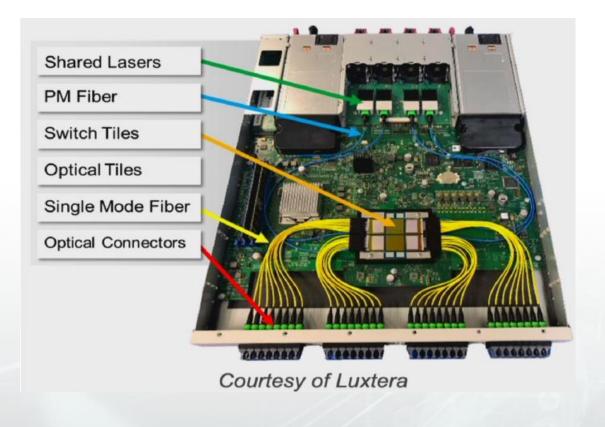
- Integration of laser source
- → Need for high-precision die bonding
- Fiber array assembly and alignment
- → Need for fiber interconnect

Machine concepts for NPI and volume production









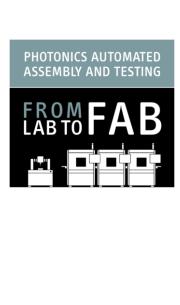
- Known good photonic integrated circuits (PICs)
- → Need for electro-optical (wafer level) testing

- Integration of laser source
- → Need for high-precision die bonding
- Fiber array assembly and alignment
- → Need for fiber interconnect

- Machine concepts for NPI and volume production
- → Need for holistic product line

From development to volume production





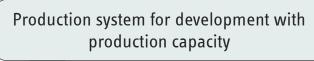
Fully automatic production line consisting of feeding system, active and passive assembly cells, end of line test and laser marking





Fully automatic production system: 1 Input feeder; 1 Assembly system;

1 Output feeder



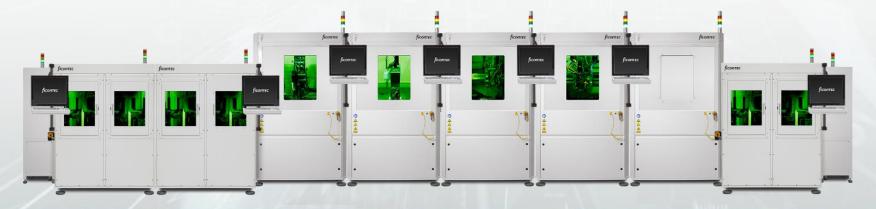
Lab systems (with production capability)





Key takeaways

- Assembly & Test are (and will remain) the cost driver for photonic products
- Product and machine development are interconnected and influence each other
- Automated assembly steps for most process steps for data center devices available
- Last decade mainly focused on improving individual assembly machine performance
- This decade will focus on increasingly higher levels of automation





Global Sales & Service



Find out more ...







C2M ■ Fraunhofer

AIM















Homepage

'ficonTEC Insider' Blog

LinkedIN / Twitter

Vimeo / YouTube

Locations & Contacts

Online:

18.04.2024





Contact:

ficonTEC service GmbH

Malte Ennen - Sales Engineer Europe

malte.ennen@ficontec.com

Im Finigen 3, 28832 Achim